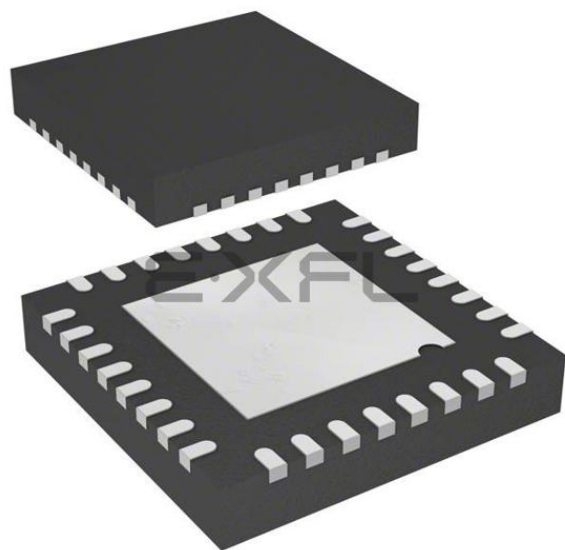




Welcome to [E-XFL.COM](https://www.e-xfl.com)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Not For New Designs
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	30
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 22x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-VFQFN Exposed Pad
Supplier Device Package	32-VFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8al3166ucy

List of tables

Table 1.	Device summary	2
Table 2.	Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x low-power device features and peripheral counts	12
Table 3.	Timer feature comparison	21
Table 4.	Legend/abbreviation	28
Table 5.	Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x pin description	28
Table 6.	Flash and RAM boundary addresses	37
Table 7.	Factory conversion registers	37
Table 8.	I/O port hardware register map	37
Table 9.	General hardware register map	38
Table 10.	CPU/SWIM/debug module/interrupt controller registers	51
Table 11.	Interrupt mapping	53
Table 12.	Option byte addresses	55
Table 13.	Option byte description	56
Table 14.	Unique ID registers (96 bits)	58
Table 15.	Voltage characteristics	60
Table 16.	Current characteristics	61
Table 17.	Thermal characteristics	61
Table 18.	Operating lifetime (OLF)	61
Table 19.	General operating conditions	62
Table 20.	Embedded reset and power control block characteristics	62
Table 21.	Total current consumption in Run mode	65
Table 22.	Total current consumption in Wait mode	67
Table 23.	Total current consumption and timing in low-power run mode at VDD = 1.65 V to 3.6 V	69
Table 24.	Total current consumption in low-power wait mode at VDD = 1.65 V to 3.6 V	70
Table 25.	Total current consumption and timing in active-halt mode at VDD = 1.65 V to 3.6 V	70
Table 26.	Typical current consumption in Active-halt mode, RTC clocked by LSE external crystal	72
Table 27.	Total current consumption and timing in Halt mode at VDD = 1.65 to 3.6 V	72
Table 28.	Peripheral current consumption	73
Table 29.	Current consumption under external reset	74
Table 30.	HSE external clock characteristics	74
Table 31.	LSE external clock characteristics	74
Table 32.	HSE oscillator characteristics	75
Table 33.	LSE oscillator characteristics	76
Table 34.	HSI oscillator characteristics	77
Table 35.	LSI oscillator characteristics	78
Table 36.	RAM and hardware registers	79
Table 37.	Flash program memory/data EEPROM memory	79
Table 38.	Flash program memory	80
Table 39.	Data memory	80
Table 40.	I/O current injection susceptibility	81
Table 41.	I/O static characteristics	81
Table 42.	Output driving current (high sink ports)	85
Table 43.	Output driving current (true open drain ports)	85
Table 44.	Output driving current (PA0 with high sink LED driver capability)	85

Table 45.	NRST pin characteristics	87
Table 46.	SPI1 characteristics	89
Table 47.	I ² C characteristics	91
Table 48.	LCD characteristics	93
Table 49.	Reference voltage characteristics	94
Table 50.	TS characteristics	94
Table 51.	Comparator 1 characteristics	95
Table 52.	Comparator 2 characteristics	96
Table 53.	DAC characteristics	96
Table 54.	DAC accuracy	98
Table 55.	DAC output on PB4-PB5-PB6	98
Table 56.	ADC1 characteristics	99
Table 57.	ADC1 accuracy with VDDA = 2.5 V to 3.3 V	101
Table 58.	ADC1 accuracy with VDDA = 2.4 V to 3.6 V	101
Table 59.	ADC1 accuracy with VDDA = VREF+ = 1.8 V to 2.4 V	102
Table 60.	R _{AIN} max for f _{ADC} = 16 MHz	103
Table 61.	EMS data	105
Table 62.	EMI data	106
Table 63.	ESD absolute maximum ratings	106
Table 64.	Electrical sensitivities	107
Table 65.	LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package mechanical data	109
Table 66.	LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data	112
Table 67.	VFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package mechanical data	115
Table 68.	Thermal characteristics	118
Table 69.	Document revision history	120

3.1 Low-power modes

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices support five low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Wait mode:** CPU clock is stopped, but selected peripherals keep running. An internal or external interrupt, event or a Reset can be used to exit the microcontroller from Wait mode (WFE or WFI mode). Wait consumption: refer to [Table 22](#).
- **Low power run mode:** The CPU and the selected peripherals are running. Execution is done from RAM with a low speed oscillator (LSI or LSE). Flash and data EEPROM are stopped and the voltage regulator is configured in ultra-low-power mode. The microcontroller enters Low power run mode by software and can exit from this mode by software or by a reset.
All interrupts must be masked. They cannot be used to exit the microcontroller from this mode. Low power run mode consumption: refer to [Table 23](#).
- **Low power wait mode:** This mode is entered when executing a Wait for event in Low power run mode. It is similar to Low power run mode except that the CPU clock is stopped. The wakeup from this mode is triggered by a Reset or by an internal or external event (peripheral event generated by the timers, serial interfaces, DMA controller (DMA1), comparators and I/O ports). When the wakeup is triggered by an event, the system goes back to Low power run mode.
All interrupts must be masked. They cannot be used to exit the microcontroller from this mode. Low power wait mode consumption: refer to [Table 24](#).
- **Active-halt mode:** CPU and peripheral clocks are stopped, except RTC. The wakeup can be triggered by RTC interrupts, external interrupts or reset. Active-halt consumption: refer to [Table 25](#) and [Table 26](#).
- **Halt mode:** CPU and peripheral clocks are stopped, the device remains powered on. The RAM content is preserved. The wakeup is triggered by an external interrupt or reset. A few peripherals have also a wakeup from Halt capability. Switching off the internal reference voltage reduces power consumption. Through software configuration it is also possible to wake up the device without waiting for the internal reference voltage wakeup time to have a fast wakeup time of 5 μ s. Halt consumption: refer to [Table 27](#).

3.13 Timers

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices contain one advanced control timer (TIM1), two 16-bit general purpose timers (TIM2 and TIM3) and one 8-bit basic timer (TIM4).

All the timers can be served by DMA1.

[Table 3](#) compares the features of the advanced control, general-purpose and basic timers.

Table 3. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA1 request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	up/down	Any integer from 1 to 65536	Yes	3 + 1	3
TIM2			Any power of 2 from 1 to 128		2	None
TIM3						
TIM4	8-bit	up	Any power of 2 from 1 to 32768		0	

3.13.1 TIM1 - 16-bit advanced control timer

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down auto reload counter with 16-bit prescaler
- Three independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output.
- One additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- Three complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.13.2 16-bit general purpose timers

- 16-bit auto reload (AR) up/down-counter
- 7-bit prescaler adjustable to fixed power of 2 ratios (1...128)
- Two individually configurable capture/compare channels
- PWM mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)
- Synchronization with other timers or external signals (external clock, reset, trigger and enable)

3.13.3 8-bit basic timer

The 8-bit timer consists of an 8-bit up auto-reload counter driven by a programmable prescaler. It can be used for timebase generation with interrupt generation on timer overflow or for DAC trigger generation.

3.14 Watchdog timers

The watchdog system is based on two independent timers providing maximum security to the applications.

3.14.1 Window watchdog timer

The window watchdog (WWDG) is used to detect the occurrence of a software fault, usually generated by external interferences or by unexpected logical conditions, which cause the application program to abandon its normal sequence.

3.14.2 Independent watchdog timer

The independent watchdog peripheral (IWDG) can be used to resolve processor malfunctions due to hardware or software failures.

It is clocked by the internal LSI RC clock source, and thus stays active even in case of a CPU clock failure.

3.15 Beeper

The beeper function outputs a signal on the BEEP pin for sound generation. The signal is in the range of 1, 2 or 4 kHz.

3.16 Communication interfaces

3.16.1 SPI

The serial peripheral interface (SPI1) provides half/ full duplex synchronous serial communication with external devices.

- Maximum speed: 8 Mbit/s ($f_{\text{SYSCLK}}/2$) both for master and slave
- Full duplex synchronous transfers
- Simplex synchronous transfers on 2 lines with a possible bidirectional data line
- Master or slave operation - selectable by hardware or software
- Hardware CRC calculation
- Slave/master selection input pin

Note: SPI1 can be served by the DMA1 Controller.

3.16.2 I²C

The I²C bus interface (I²C1) provides multi-master capability, and controls all I²C bus-specific sequencing, protocol, arbitration and timing.

- Master, slave and multi-master capability
- Standard mode up to 100 kHz and fast speed modes up to 400 kHz
- 7-bit and 10-bit addressing modes
- SMBus 2.0 and PMBus support
- Hardware CRC calculation

Note: I²C1 can be served by the DMA1 Controller.

3.16.3 USART

The USART interface (USART1) allows full duplex, asynchronous communications with external devices requiring an industry standard NRZ asynchronous serial data format. It offers a very wide range of baud rates.

- 1 Mbit/s full duplex SCI
- SPI1 emulation
- High precision baud rate generator
- SmartCard emulation
- IrDA SIR encoder decoder
- Single wire half duplex mode

Note: USART1 can be served by the DMA1 Controller.

USART1 can be used to implement LIN slave communication, with LIN Break detection on the framing error flag (FE in USART_SR register) with a value of 0 in the USART data register (USART_DR).

3.17 Infrared (IR) interface

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices contain an infrared interface which can be used with an IR LED for remote control functions. Two timer output compare channels are used to generate the infrared remote control signals.

3.18 Development support

Development tools

Development tools for the STM8 microcontrollers include:

- The STice emulation system offering tracing and code profiling
- The STVD high-level language debugger including C compiler, assembler and integrated development environment.
- The STVP Flash programming software

The STM8 also comes with starter kits, evaluation boards and low-cost in-circuit debugging/programming tools.

Single wire data interface (SWIM) and debug module

The debug module with its single wire data interface (SWIM) permits non-intrusive real-time in-circuit debugging and fast memory programming.

The Single wire interface is used for direct access to the debugging module and memory programming. The interface can be activated in all device operation modes.

The non-intrusive debugging module features a performance close to a full-featured emulator. Beside memory and peripherals, CPU operation can also be monitored in real-time by means of shadow registers.

Bootloader

A bootloader is available to reprogram the Flash memory using the USART1 interface. The reference document for the bootloader is *UM0560: STM8 bootloader user manual*.

Table 5. Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48	VQFPN32	LQFP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
38	26	26	PC1 ⁽⁵⁾ /I2C1_SCL	I/O	FT	<u>X</u>	-	X	-	T ⁽⁷⁾		Port C1	I2C1 clock
41	27	27	PC2/USART1_RX/ LCD_SEG22/ADC1_IN6/ COMP1_INP/REFINT	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C2	USART1 receive / LCD segment 22 / ADC1_IN6 / Comparator 1 positive input / Internal voltage reference output
42	28	28	PC3/USART1_TX/ LCD_SEG23 ⁽²⁾ / ADC1_IN5/COMP1_INP/ COMP2_INM	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C3	USART1 transmit / LCD segment 23 / ADC1_IN5 / Comparator 1 positive input / Comparator 2 negative input
43	29	29	PC4/USART1_CK/ I2C1_SMB/CCO/ LCD_SEG24 ⁽²⁾ / ADC1_IN4/COMP2_INM/ COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C4	USART1 synchronous clock / I2C1_SMB / Configurable clock output / LCD segment 24 / ADC1_IN4 / Comparator 2 negative input / Comparator 1 positive input
44	30	30	PC5/OSC32_IN /[SPI1_NSS] ⁽⁴⁾ / [USART1_TX] ⁽⁴⁾	I/O	-	<u>X</u>	X	X	HS	X	X	Port C5	LSE oscillator input / [SPI1 master/slave select] / [USART1 transmit]
45	31	31	PC6/OSC32_OUT/ [SPI1_SCK] ⁽⁴⁾ / [USART1_RX] ⁽⁴⁾	I/O	-	<u>X</u>	X	X	HS	X	X	Port C6	LSE oscillator output / [SPI1 clock] / [USART1 receive]
46	-	-	PC7/LCD_SEG25 ⁽²⁾ / ADC1_IN3/COMP2_INM/ COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port C7	LCD segment 25 /ADC1_IN3/ Comparator negative input / Comparator 1 positive input

Table 5. Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x pin description (continued)

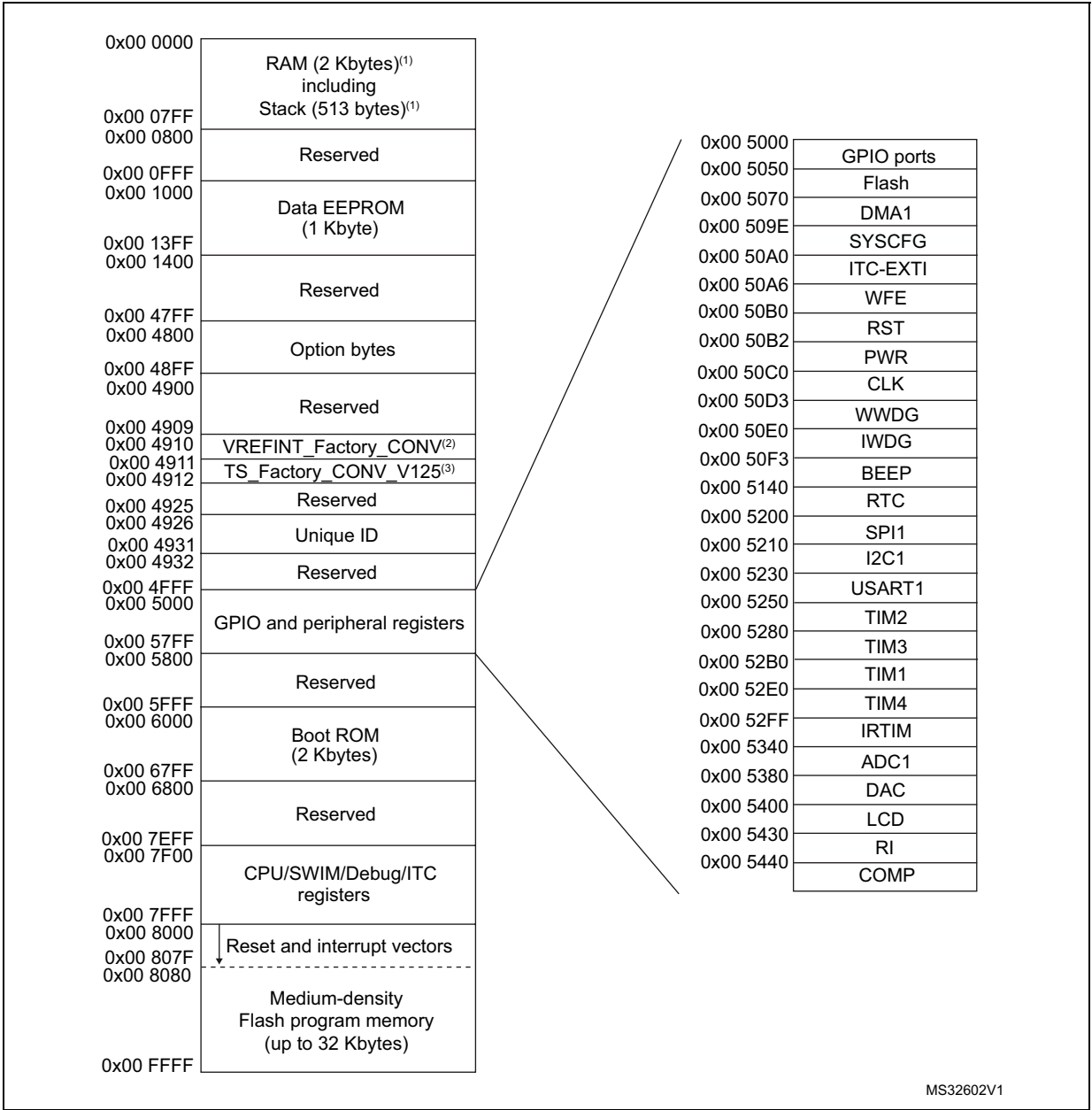
Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48	VFQFPN32	LQFP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
20	-	-	PD0/TIM3_CH2/ [ADC1_TRIG] ⁽⁴⁾ / LCD_SEG7 ⁽²⁾ /ADC1_IN2 2/COMP2_INP/ COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D0	Timer 3 - channel 2 / [ADC1_Trigger] / LCD segment 7 / ADC1_IN22 / Comparator 2 positive input / Comparator 1 positive input
-	9	9	PD0/TIM3_CH2/ [ADC1_TRIG] ⁽⁴⁾ / ADC1_IN22/COMP2_INP / COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D0 ⁽⁸⁾	Timer 3 - channel 2 / [ADC1_Trigger] / ADC1_IN22 / Comparator 2 positive input / Comparator 1 positive input
21	-	-	PD1/TIM3_ETR/ LCD_COM3 ⁽²⁾ / ADC1_IN21/COMP2_INP / COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D1	Timer 3 - trigger / LCD_COM3 / ADC1_IN21 / Comparator 2 positive input / Comparator 1 positive input
-	10	10	PD1/TIM1_CH3N/ [TIM3_ETR] ⁽⁴⁾ / LCD_COM3 ⁽²⁾ / ADC1_IN21/COMP2_INP / COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D1	[Timer 3 - trigger]/ TIM1 inverted channel 3 / LCD_COM3/ ADC1_IN21 / Comparator 2 positive input / Comparator 1 positive input
22	11	11	PD2/TIM1_CH1 /LCD_SEG8 ⁽²⁾ / ADC1_IN20/COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D2	Timer 1 - channel 1 / LCD segment 8 / ADC1_IN20 / Comparator 1 positive input
23	12	12	PD3/ TIM1_ETR/ LCD_SEG9 ⁽²⁾ /ADC1_IN1 9/COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D3	Timer 1 - trigger / LCD segment 9 / ADC1_IN19 / Comparator 1 positive input
33	21	21	PD4/TIM1_CH2 /LCD_SEG18 ⁽²⁾ / ADC1_IN10/COMP1_INP	I/O	TT ⁽³⁾	<u>X</u>	X	X	HS	X	X	Port D4	Timer 1 - channel 2 / LCD segment 18 / ADC1_IN10/ Comparator 1 positive input

5 Memory and register map

5.1 Memory mapping

The memory map is shown in [Figure 9](#).

Figure 9. Memory map



MS32602V1

1. [Table 6](#) lists the boundary addresses for each memory size. The top of the stack is at the RAM end address.
2. The VREFINT_Factory_CONV byte represents the LSB of the V_{REFINT} 12-bit ADC conversion result. The MSB have a fixed value: 0x6.
3. The TS_Factory_CONV_V125 byte represents the LSB of the V₁₂₅ 12-bit ADC conversion result. The MSB have a fixed value: 0x3. The V₁₂₅ measurement is performed at 125°C.
4. Refer to [Table 9](#) for an overview of hardware register mapping, to [Table 8](#) for details on I/O port hardware registers, and to [Table 10](#) for information on CPU/SWIM/debug module controller registers.

Table 6. Flash and RAM boundary addresses

Memory area	Size	Start address	End address
RAM	2 Kbyte	0x00 0000	0x00 07FF
Flash program memory	8 Kbyte	0x00 8000	0x00 9FFF
	16 Kbyte		0x00 BFFF
	32 Kbyte		

5.2 Register map

Table 7. Factory conversion registers

Address	Block	Register label	Register name	Reset status
0x00 4910	-	VREFINT_Factory_CONV ⁽¹⁾	Internal reference voltage factory conversion	0xXX
0x00 4911	-	TS_Factory_CONV_V125 ⁽²⁾	Temperature sensor output voltage	0xXX

1. The VREFINT_Factory_CONV byte represents the 8 LSB of the result of the VREFINT 12-bit ADC conversion performed in factory. The MSB have a fixed value: 0x6.
2. The TS_Factory_CONV_V125 byte represents the 8 LSB of the result of the V125 12-bit ADC conversion performed in factory. The 2 MSB have a fixed value: 0x3.

Table 8. I/O port hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5000	Port A	PA_ODR	Port A data output latch register	0x00
0x00 5001		PA_IDR	Port A input pin value register	0xXX
0x00 5002		PA_DDR	Port A data direction register	0x00
0x00 5003		PA_CR1	Port A control register 1	0x01
0x00 5004		PA_CR2	Port A control register 2	0x00
0x00 5005	Port B	PB_ODR	Port B data output latch register	0x00
0x00 5006		PB_IDR	Port B input pin value register	0xXX
0x00 5007		PB_DDR	Port B data direction register	0x00
0x00 5008		PB_CR1	Port B control register 1	0x00
0x00 5009		PB_CR2	Port B control register 2	0x00
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PB_IDR	Port C input pin value register	0xXX
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00

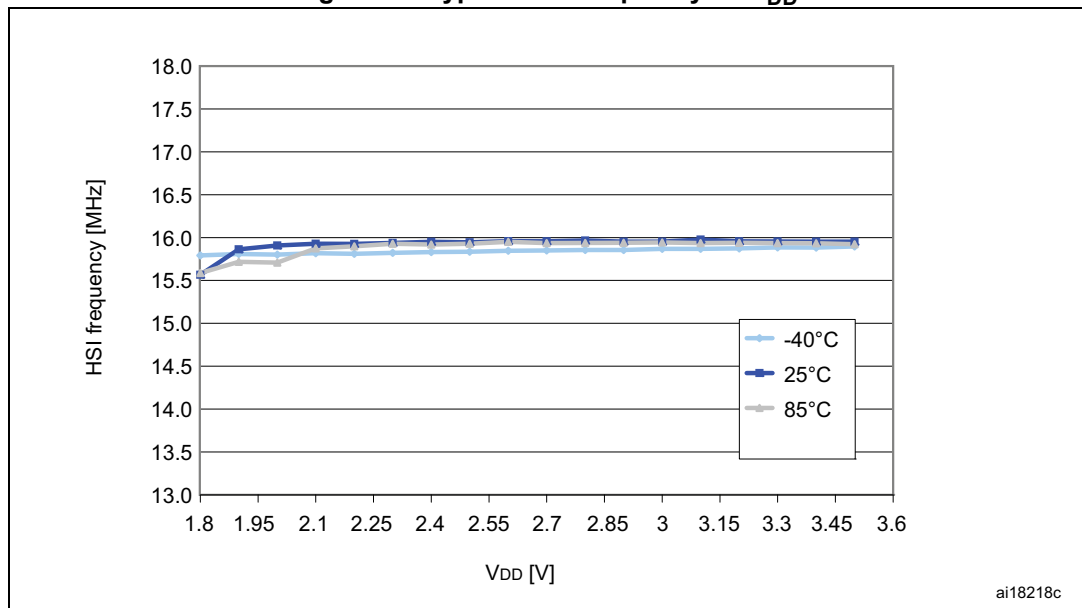
Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5352 to 0x00 537F	Reserved area (46 bytes)			
0x00 5380	DAC	DAC_CR1	DAC control register 1	0x00
0x00 5381		DAC_CR2	DAC control register 2	0x00
0x00 5382 to 0x00 5383		Reserved area (2 bytes)		
0x00 5384		DAC_SWTRIGR	DAC software trigger register	0x00
0x00 5385		DAC_SR	DAC status register	0x00
0x00 5386 to 0x00 5387		Reserved area (2 bytes)		
0x00 5388		DAC_RDHRH	DAC right aligned data holding register high	0x00
0x00 5389		DAC_RDHRL	DAC right aligned data holding register low	0x00
0x00 538A to 0x00 538B		Reserved area (2 bytes)		
0x00 538C		DAC_LDHRH	DAC left aligned data holding register high	0x00
0x00 538D		DAC_LDHRL	DAC left aligned data holding register low	0x00
0x00 538E to 0x00 538F		Reserved area (2 bytes)		
0x00 5390		DAC_DHR8	DAC 8-bit data holding register	0x00
0x00 5391 to 0x00 53AB		Reserved area (27 bytes)		
0x00 53AC		DAC_DORH	DAC data output register high	0x00
0x00 53AD		DAC_DORL	DAC data output register low	0x00
0x00 53AE to 0x00 53FF	Reserved area (82 bytes)			
0x00 5400	LCD	LCD_CR1	LCD control register 1	0x00
0x00 5401		LCD_CR2	LCD control register 2	0x00
0x00 5402		LCD_CR3	LCD control register 3	0x00
0x00 5403		LCD_FRQ	LCD frequency selection register	0x00
0x00 5404		LCD_PM0	LCD Port mask register 0	0x00
0x00 5405		LCD_PM1	LCD Port mask register 1	0x00
0x00 5406		LCD_PM2	LCD Port mask register 2	0x00
0x00 5407		LCD_PM3	LCD Port mask register 3	0x00
0x00 5408 to 0x00 540B	Reserved area (4 bytes)			

Table 11. Interrupt mapping (continued)

IRQ No.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Wakeup from Wait (WFI mode)	Wakeup from Wait (WFE mode) ⁽¹⁾	Vector address
18	COMP1/ COMP2/ ADC1	COMP1 interrupt/ COMP2 interrupt ADC1 end of conversion/ analog watchdog/ overrun interrupt	Yes	Yes	Yes	Yes	0x00 8050
19	TIM2	TIM2 update/overflow/ trigger/break interrupt	-	-	Yes	Yes	0x00 8054
20	TIM2	TIM2 capture/compare interrupt	-	-	Yes	Yes	0x00 8058
21	TIM3	TIM3 update /overflow/ trigger/break interrupt	-	-	Yes	Yes	0x00 805C
22	TIM3	TIM3 capture/compare interrupt	-	-	Yes	Yes	0x00 8060
23	TIM1	TIM1 update /overflow/ trigger/COM	-	-	-	Yes	0x00 8064
24	TIM1	TIM1 capture/compare interrupt	-	-	-	Yes	0x00 8068
25	TIM4	TIM4 update /overflow/ trigger interrupt	-	-	Yes	Yes	0x00 806C
26	SPI1	SPI TX buffer empty/RX buffer not empty/error/wakeup interrupt	Yes	Yes	Yes	Yes	0x00 8070
27	USART1	USART1 transmit data register empty/ transmission complete interrupt	-	-	Yes	Yes	0x00 8074
28	USART 1	USART1 received data ready/overrun error/ idle line detected/parity error/global error interrupt	-	-	Yes	Yes	0x00 8078
29	I ² C1	I ² C1 interrupt ⁽³⁾	Yes	Yes	Yes	Yes	0x00 807C

1. The Low power wait mode is entered when executing a WFE instruction in Low power run mode. In WFE mode, the interrupt is served if it has been previously enabled. After processing the interrupt, the processor goes back to WFE mode. When the interrupt is configured as a wakeup event, the CPU wakes up and resumes processing.
2. The interrupt from PVD is logically OR-ed with Port E and F interrupts. Register EXT1_CONF allows to select between Port E and Port F interrupt (see [External interrupt port select register \(EXT1_CONF\)](#) in STM8L051/L052 Value Line, STM8L151/L152, STM8L162, STM8AL31, STM8AL3L MCU lines reference manual (RM0031)).
3. The device is woken up from Halt or Active-halt mode only when the address received matches the interface address.

Figure 17. Typical HSI frequency vs V_{DD} 

Low speed internal RC oscillator (LSI)

In the following table, data are based on characterization results, not tested in production.

Table 35. LSI oscillator characteristics

Symbol	Parameter ⁽¹⁾	Conditions ⁽¹⁾	Min	Typ	Max	Unit
f_{LSI}	Frequency	-	26	38	56	kHz
$t_{su(LSI)}$	LSI oscillator wakeup time	-	-	-	200 ⁽²⁾	μ s
$I_{DD(LSI)}$	LSI oscillator frequency drift ⁽³⁾	$0\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$	-12	-	11	%

1. $V_{DD} = 1.65\text{ V}$ to 3.6 V , $T_A = -40$ to $125\text{ }^{\circ}\text{C}$ unless otherwise specified.

2. Guaranteed by design.

3. This is a deviation for an individual part, once the initial frequency has been measured.

Table 40. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I _{INJ}	Injected current on true open-drain pins (PC0 and PC1)	-5	+0	mA
	Injected current on all five-volt tolerant (FT) pins	-5	+0	
	Injected current on all 3.6 V tolerant (TT) pins	-5	+0	
	Injected current on any other pin	-5	+5	

9.3.7 I/O port pin characteristics

General characteristics

Subject to general operating conditions for V_{DD} and T_A unless otherwise specified. All unused pins must be kept at a fixed voltage: using the output mode of the I/O for example or an external pull-up or pull-down resistor.

Table 41. I/O static characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min	Typ	Max	Unit
V _{IL}	Input low level voltage	Input voltage on all pins	$V_{SS}-0.3$	-	$0.3 \times V_{DD}$	V
V _{IH}	Input high level voltage	Input voltage on true open-drain pins (PC0 and PC1) with $V_{DD} < 2$ V	$0.70 \times V_{DD}$	-	5.2 ⁽²⁾	
		Input voltage on true open-drain pins (PC0 and PC1) with $V_{DD} \geq 2$ V		-	5.5 ⁽²⁾	
		Input voltage on five-volt tolerant (FT) pins (PA7 and PE0) with $V_{DD} < 2$ V	$0.70 \times V_{DD}$	-	5.2 ⁽²⁾	
		Input voltage on five-volt tolerant (FT) pins (PA7 and PE0) with $V_{DD} \geq 2$ V		-	5.5 ⁽²⁾	
		Input voltage on 3.6 V tolerant (TT) pins		-	3.6 ⁽²⁾	
		Input voltage on any other pin	$0.70 \times V_{DD}$	-	$V_{DD}+0.3$ ⁽²⁾	
V _{hys}	Schmitt trigger voltage hysteresis ⁽³⁾	I/Os	-	200	-	mV
		True open drain I/Os	-	200	-	
I _{lkg}	Input leakage current ⁽⁴⁾	$V_{SS} \leq V_{IN} \leq V_{DD}$ High sink I/Os	-	-	50	nA
		$V_{SS} \leq V_{IN} \leq V_{DD}$ True open drain I/Os	-	-	200	
		$V_{SS} \leq V_{IN} \leq V_{DD}$ PA0 with high sink LED driver capability	-	-	200	

Table 49. Reference voltage characteristics

Symbol	Parameter	Conditions	Min	Typ	Max.	Unit
I_{REFINT}	Internal reference voltage consumption	-	-	1.4	-	μA
$T_{S_VREFINT}^{(1)(2)}$	ADC sampling time when reading the internal reference voltage	-	-	5	10	μs
$I_{BUF}^{(2)}$	Internal reference voltage buffer consumption (used for ADC)	-	-	13.5	25	μA
$V_{REFINT\ out}$	Reference voltage output	-	1.202 ₍₃₎	1.224	1.242 ₍₃₎	V
$I_{LPBUF}^{(2)}$	Internal reference voltage low power buffer consumption (used for comparators or output)	-	-	730	1200	nA
$I_{REFOUT}^{(2)}$	Buffer output current ⁽⁴⁾	-	-	-	1	μA
C_{REFOUT}	Reference voltage output load	-	-	-	50	pF
$t_{VREFINT}$	Internal reference voltage startup time	-	-	2	3	ms
$t_{BUFEN}^{(2)}$	Internal reference voltage buffer startup time once enabled ⁽¹⁾	-	-	-	10	μs
$ACC_{VREFINT}$	Accuracy of V_{REFINT} stored in the $VREFINT_Factory_CONV$ byte ⁽⁵⁾	-	-	-	± 5	mV
$STAB_{VREFINT}^{(2)}$	Stability of V_{REFINT} over temperature	$-40\ ^\circ C \leq T_A \leq 125\ ^\circ C$	-	20	50	ppm/ $^\circ C$
	Stability of V_{REFINT} over temperature	$0\ ^\circ C \leq T_A \leq 50\ ^\circ C$	-	-	20	
$STAB_{VREFINT}^{(2)}$	Stability of V_{REFINT} after 1000 hours	-	-	-	1000	ppm

1. Defined when ADC output reaches its final value $\pm 1/2LSB$

2. Guaranteed by design.

3. Tested in production at $V_{DD} = 3\ V \pm 10\ mV$.

4. To guaranty less than 1% V_{REFOUT} deviation.

5. Measured at $V_{DD} = 3\ V \pm 10\ mV$. This value takes into account V_{DD} accuracy and ADC conversion accuracy.

9.3.11 Temperature sensor

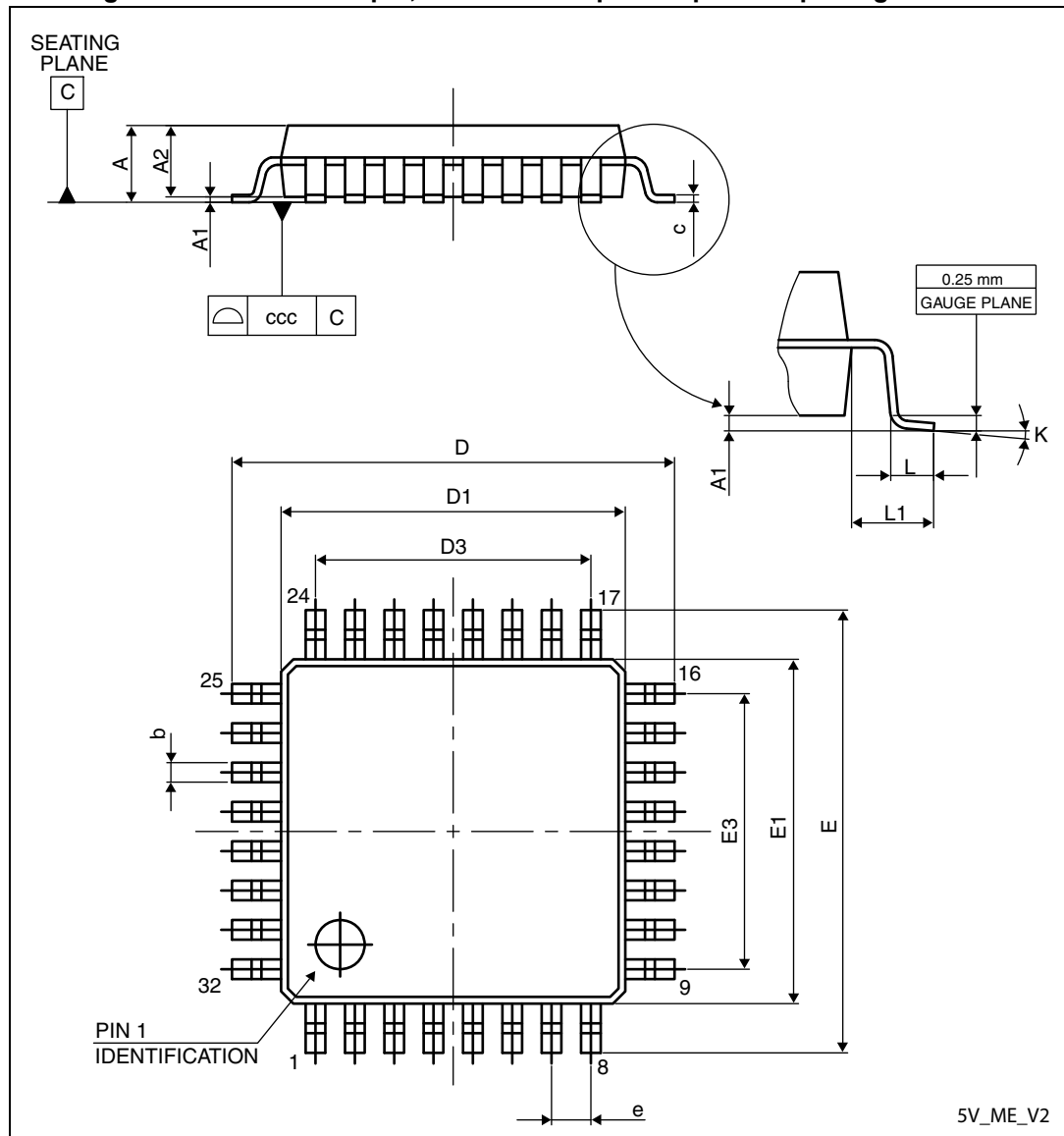
In the following table, data are based on characterization results, not tested in production, unless otherwise specified.

Table 50. TS characteristics

Symbol	Parameter	Min	Typ	Max.	Unit
$V_{125}^{(1)}$	Sensor reference voltage at $125\ ^\circ C \pm 5\ ^\circ C$	0.640	0.660	0.680	V
T_L	V_{SENSOR} linearity with temperature	-	± 1	± 2	$^\circ C$
Avg_slope	Average slope	1.59 ⁽²⁾	1.62	1.65 ⁽²⁾	mV/ $^\circ C$
$I_{DD(TEMP)}$	Consumption	-	3.4	6 ⁽²⁾	μA

10.3 LQFP32 package information

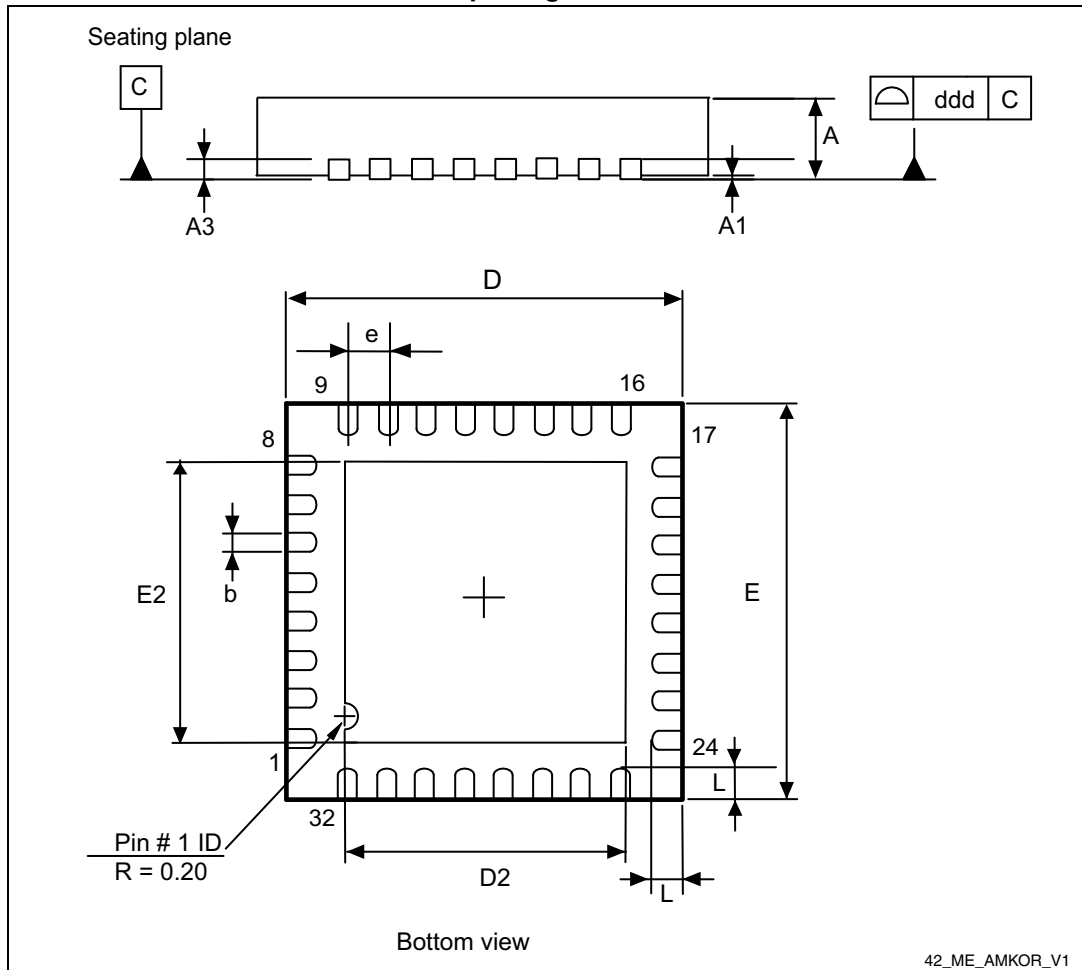
Figure 44. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.

10.4 VFQFPN32 package information

Figure 47. VFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package outline



1. Drawing is not to scale.
2. There is an exposed die pad on the underside of the VQFPN package. It is recommended to connect and solder this backside pad to the PCB ground.

Table 67. VFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	0.800	0.900	1.000	0.0315	0.0354	0.0394
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
A3	-	0.200	-	-	0.0079	-
b	0.180	0.250	0.300	0.0071	0.0098	0.0118
D	4.850	5.000	5.150	0.1909	0.1969	0.2028
D2	3.500	3.600	3.700	0.1378	0.1417	0.1457
E	4.850	5.000	5.150	0.1909	0.1969	0.2028
E2	3.500	3.600	3.700	0.1378	0.1417	0.1457
e	-	0.500	-	-	0.0197	-
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
ddd	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

12 Revision history

Table 69. Document revision history

Date	Revision	Changes
04-Jan-2012	1	Initial release
20-Dec-2012	2	Added consumption values when run from Flash or from RAM. Added 8k Flash devices STM8AL3138 and STM8AL3136 to Table 1: Device summary, Table 2: Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x low-power device features and peripheral counts, and Figure 50: Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x ordering information scheme. Added footnotes stating that power consumption has not been tested to Table 21 and Table 22 for HSE, and to Table 23 and Table 24 for LSE. Updated max LSI amperage values in Table 23 and Table 24. Replaced Table 38: Flash program memory and Table 39: Data memory. Added a production test footnote to Table 50: TS characteristics. Updated voltage values in Table 50: TS characteristics, and current values in Table 51: Comparator 1 characteristics and Table 52: Comparator 2 characteristics. Removed Figure 13: Typ. $I_{DD(LPR)}$ vs. V_{DD} (LSI clock source) and Figure 14: Typ. $I_{DD(LPW)}$ vs. V_{DD} (LSI clock source).
03-Jun-2013	3	Updated 'Qualification conforms' bullet on cover page. Updated 'TS_Factory_CONV' in Figure 9: Memory map Removed 'rev G' in Table 18: Operating lifetime (OLF) Ratings Replaced 0.40 by 0.38 in Table 22: Total current consumption in Wait mode 'code executed from Flash' fcpu = 125 kHz Updated footnote ⁽³⁾ in Table 23: Total current consumption and timing in low-power run mode at VDD = 1.65 V to 3.6 V, Table 24: Total current consumption in low-power wait mode at VDD = 1.65 V to 3.6 V and Table 27: Total current consumption and timing in Halt mode at VDD = 1.65 to 3.6 V Updated footnote ⁽²⁾ in Table 26: Typical current consumption in Active-halt mode, RTC clocked by LSE external crystal Updated max ILEAK_HSE in Table 30: HSE external clock characteristics and Table 31: LSE external clock characteristics Updated ACC_{HSI} in Table 34: HSI oscillator characteristics Updated tprog max Table 38: Flash program memory Updated STAB_{VREFINT} in Table 49: Reference voltage characteristics Updated 'TS_Factory_CONV' in Table 50: TS characteristics footnote. Updated 'tconv' and 'title' in Table 56: ADC1 characteristics Updated title in Table 57: ADC1 accuracy with VDDA = 2.5 V to 3.3 V Updated Table 64: Electrical sensitivities
14-Jun-2013	4	Updated max LSI measures in Table 23: Total current consumption and timing in low-power run mode at VDD = 1.65 V to 3.6 V and Table 24: Total current consumption in low-power wait mode at VDD = 1.65 V to 3.6 V